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<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. CISCP647 Application No.: 09/469,715 Inventor Gardner et al. Group 2739 Filing Date December 7, 2000
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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
HN	A	5,732,113	03/24/98	Schmidl et al.	375	355	06/20/96
HN	B	5,282,222	06/25/94	Fattouche et al.	375	1	03/31/92

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No
HN	C	EP 0823804A2	11.02.1998	EPO	H04L	27/26		

**Other Documents**

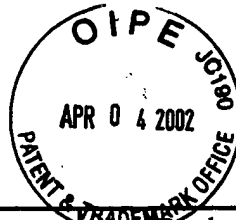
Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
HN	D	Nogami et al., "A Frequency and Timing Period Acquisition Technique for OFDM Systems", 1995, IEEE.
HN	E	Schmidl et al., "Low-Overhead, Low-Complexity [Burst] Synchronization for OFDM", Stanford University.
HN	F	Sandell et al., "Timing and Frequency Synchronization in OFDM Systems Using the Cyclic Prefix", Luleå University of Technology, Sweden.
Examiner	Hanh Nguyen	
Date Considered		<del>8/4/03</del> 3/10/04 HN

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Docket No. CISCP647 Application No.: 09/469,715 Inventor James M. Gardner et al. Group 2739 Filing Date December 21, 1999
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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
HN	A	6,252,908	6/26/01	Tore	375	259	11/17/99
HN	B	5,625,651	4/29/97	Cioffi	375	354	6/2/94
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**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	L							
	M							
	N							
	O							
	P							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	
	S	
	T	

Examiner <u>Hank Nguyen</u>	Date Considered <u>8/4/03</u>
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Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.